

IFX1021SJ

LIN Transceiver

Data Sheet

Rev. 1.0, 2011-09-20

Standard Power

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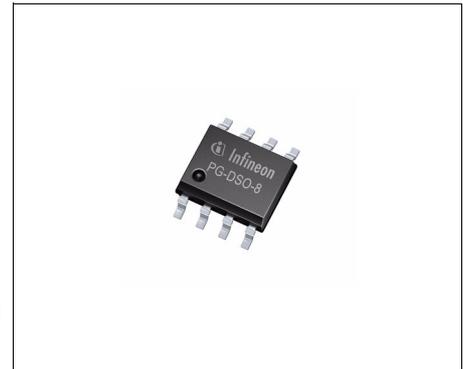
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1 Overview

Features

- Single-wire transceiver
- Transmission rate up to 20 kBaud
- Compliant to LIN specification 1.3, 2.0 and 2.1
- Very high ESD robustness of 6 kV (HBM)
- Optimized for low electromagnetic emission (EME)
- Optimized for high immunity against electromagnetic interference (EMI)
- Very low current consumption in sleep mode with Wake-Up functions
- Wake-Up source detection
- Very low leakage current on the BUS output
- Digital I/O levels compatible for 3.3 V and 5 V microcontrollers
- Bus short to V_S protection and Bus short to GND handling
- Over temperature protection and Under voltage detection
- Flash mode
- Green Product (RoHS compliant)


PG-DSO-8

For automotive applications please refer to the Infineon TLE- series of transceiver products.

Description

The IFX1021SJ is a transceiver for the Local Interconnect Network (LIN) with integrated Wake-Up and protection features. It is designed for data transmission rates from 2.4 kBaud to 20 kBaud. The IFX1021SJ serves as a bus driver between the protocol controller and the physical bus inside the LIN network. The IFX1021SJ is compliant to all LIN standards and offers a wide operational supply range up to 40V.

Different operation modes and the INH output allow the IFX1021SJ to control external components like e.g. voltage regulators. In Sleep-mode the IFX1021SJ draws less than 8 μ A of quiescent current while still being capable of "wake up" by LIN bus traffic and a local Wake-Up input. The very low leakage current on the BUS pin makes the IFX1021SJ especially suitable for partially supplied networks and supports the low quiescent current requirements of the LIN network.

The IFX1021SJ provides excellent ESD Robustness combined with a very high electromagnetic immunity (EMI) and it reaches a very low level of electromagnetic emission (EME) within a broad frequency range. It is moreover tailored to withstand harsh operating conditions.

Type	Package	Marking
IFX1021SJ	PG-DSO-8	1021SJ

2 Block Diagram

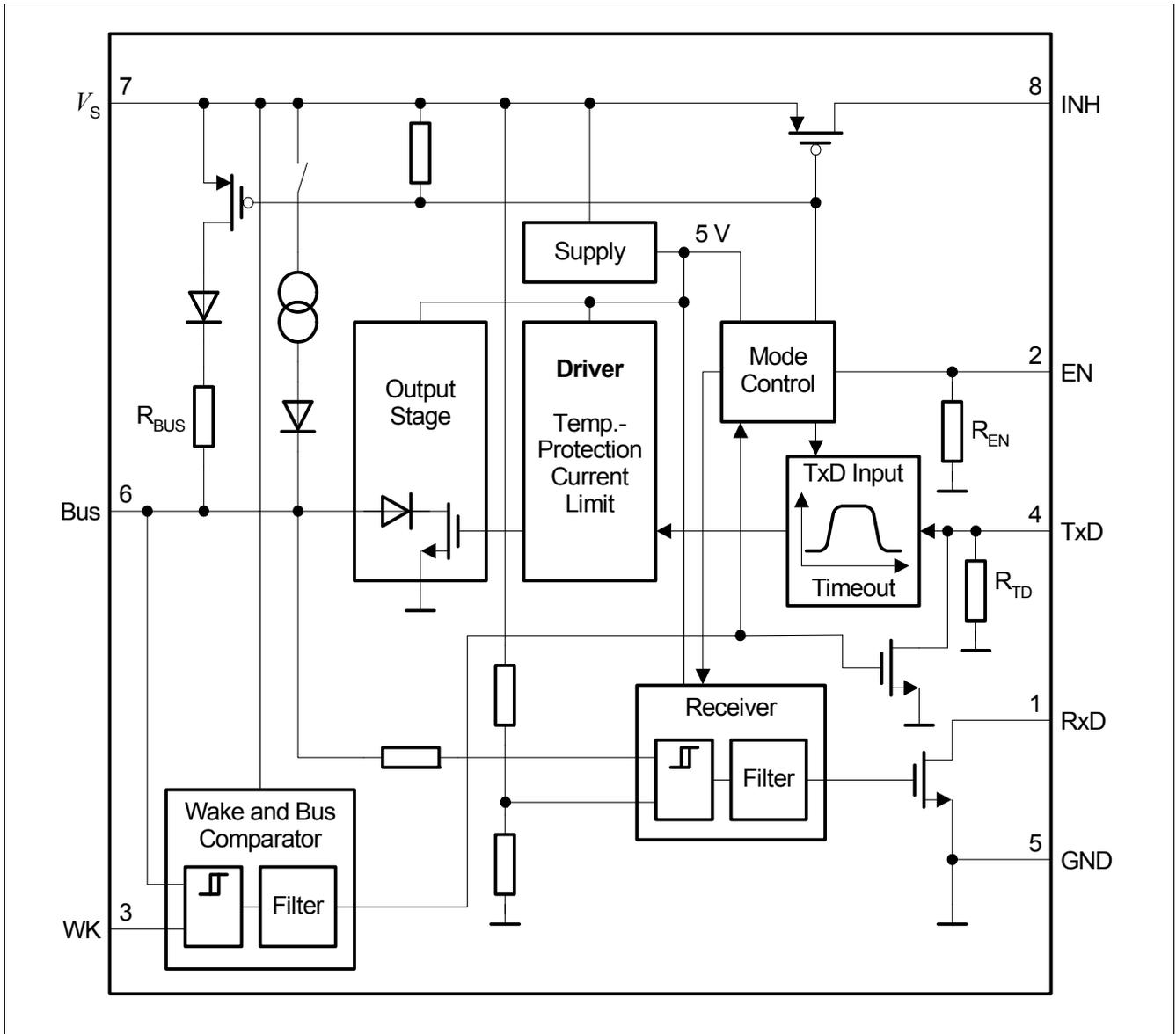


Figure 1 Block Diagram

3 Pin Configuration

3.1 Pin Assignment

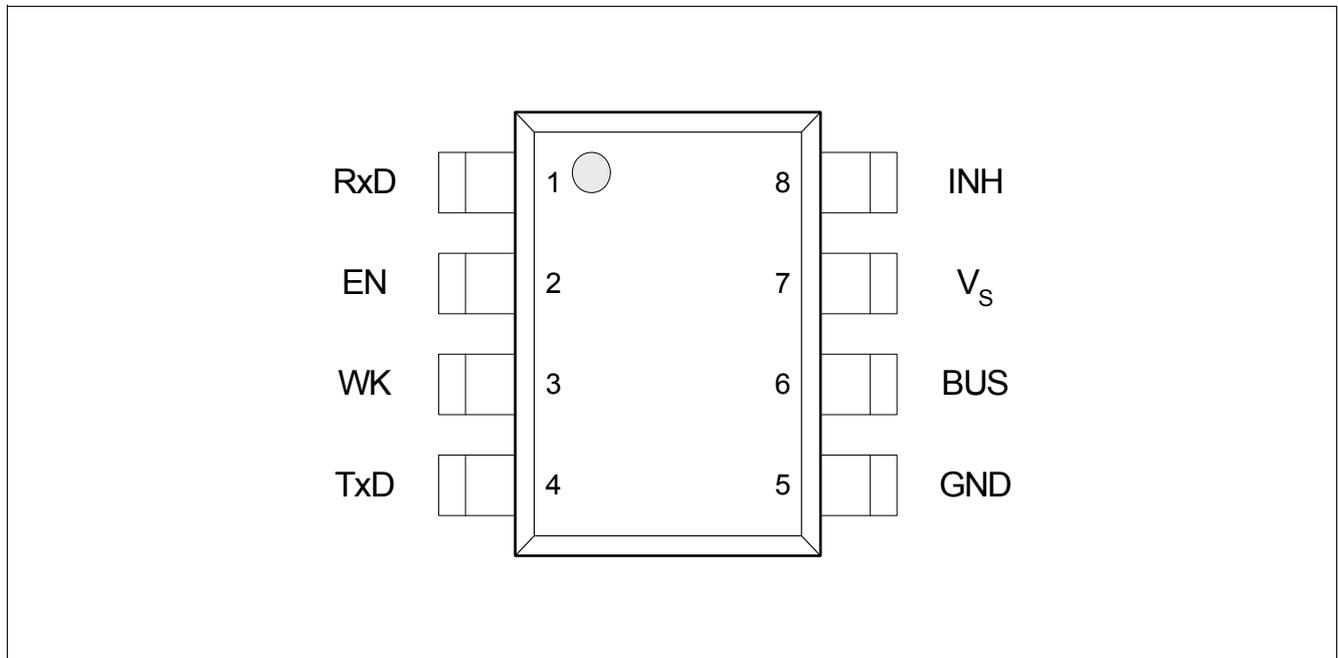


Figure 2 Pin Configuration IFX1021SJ

3.2 Pin Definitions and Functions

Pin	Symbol	Function
1	RxD	Receive data output; External Pull Up necessary LOW in dominant state, active LOW after a Wake-Up event at BUS or WK pin
2	EN	Enable input; integrated pull-down, device set to normal operation mode when HIGH
3	WK	Wake input; active LOW, negative edge triggered, internal pull-up
4	TxD	Transmit data input; integrated pull-down, LOW in dominant state; active LOW after Wake-Up via WK pin
5	GND	Ground
6	BUS	Bus input / output; LIN bus line input / output LOW in dominant state Internal termination and pull-up current source

Pin Configuration

Pin	Symbol	Function
7	V_S	Supply input (e.g. battery, ACDC, DCDC, etc)
8	INH	Inhibit output; V_S related output HIGH (V_S) in Normal and Stand-By operation mode can be used to control an external voltage regulator can be used to control external bus termination resistor when the device will be used as Master node. For further details please see also “BUS Short to GND Feature” on Page 15

4 Functional Description

The LIN Bus is a bi-directional single wire bus. The LIN Transceiver IFX1021SJ is the interface between the microcontroller and the physical LIN Bus (see [Figure 14](#) and [Figure 15](#)). The logical values of the microcontroller are driven to the LIN bus via the TxD input of the IFX1021SJ. The transmit data stream on the TxD input is converted to a LIN bus signal with optimized slew rate to minimize the EME level of the LIN network. The RxD output reads back the information from the LIN bus to the microcontroller. The receiver has an integrated filter network to suppress noise on the LIN Bus and to increase the EMI (Electro Magnetic Immunity) level of the transceiver.

Two logical states are possible on the LIN bus according to the LIN Specification 2.1 (see [Figure 3](#)):

In dominant state, the voltage on the LIN bus is set to the GND level. In recessive state, the voltage on the LIN bus is set to the supply voltage V_S . By setting the TxD input of the IFX1021SJ to “Low” the transceiver generates a dominant level on the BUS interface pin. The RxD output reads back the signal on the LIN bus and indicates a dominant LIN bus signal with a logical “Low” to the microcontroller. Setting the TxD pin to “High” the transceiver IFX1021SJ sets the LIN interface pin BUS to the recessive level, at the same time the recessive level on the LIN bus is indicated by a logical “High” on the RxD output.

Every LIN network consists of a master node and one or more slave nodes. To configure the IFX1021SJ for master node applications, a resistor in the range of 1 k Ω and a reverse diode must be connected between the LIN bus and the power supply V_S or the INH pin of the IFX1021SJ (see [Figure 14](#) and [Figure 15](#)).

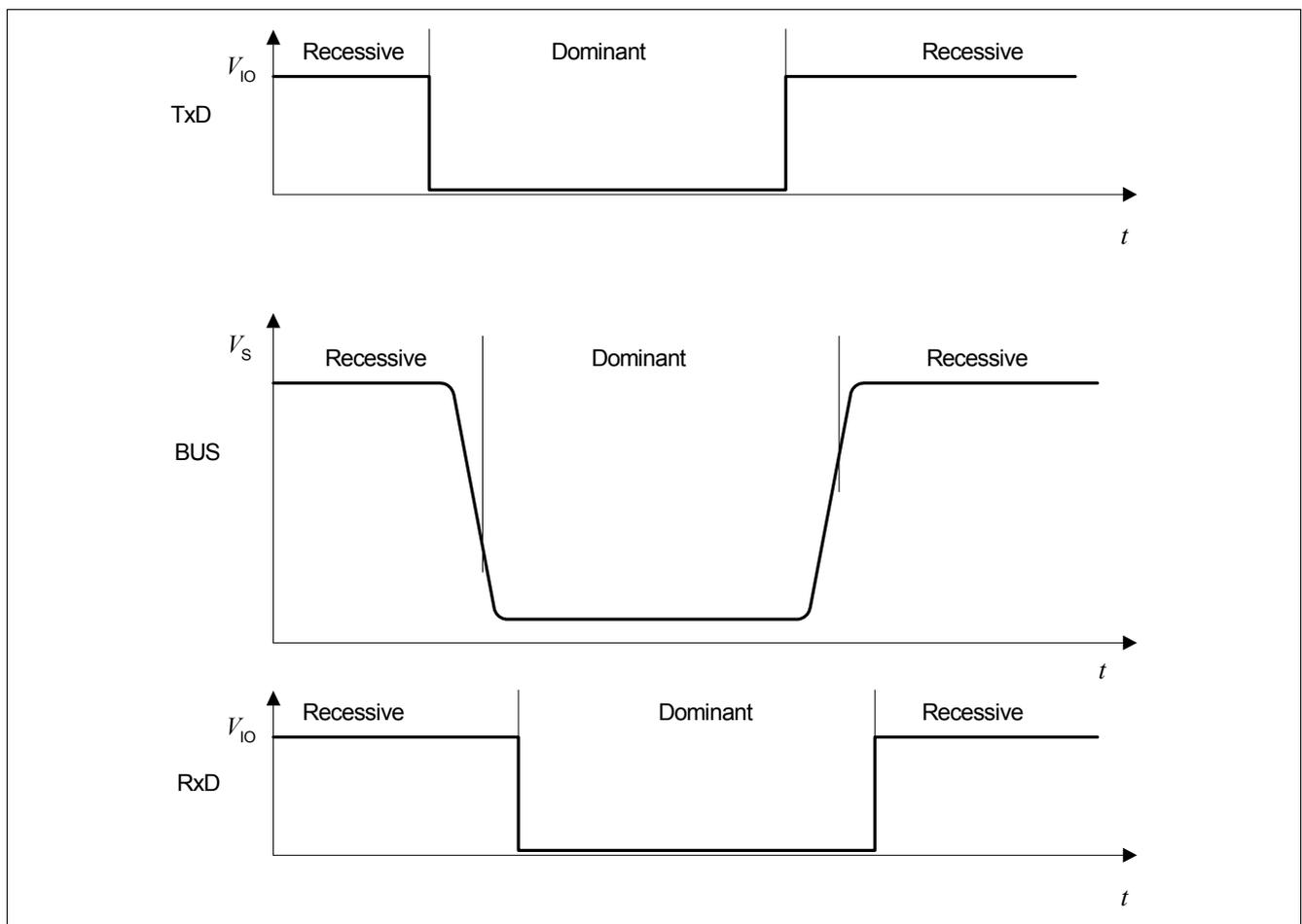


Figure 3 LIN bus signals

4.1 Operating Modes

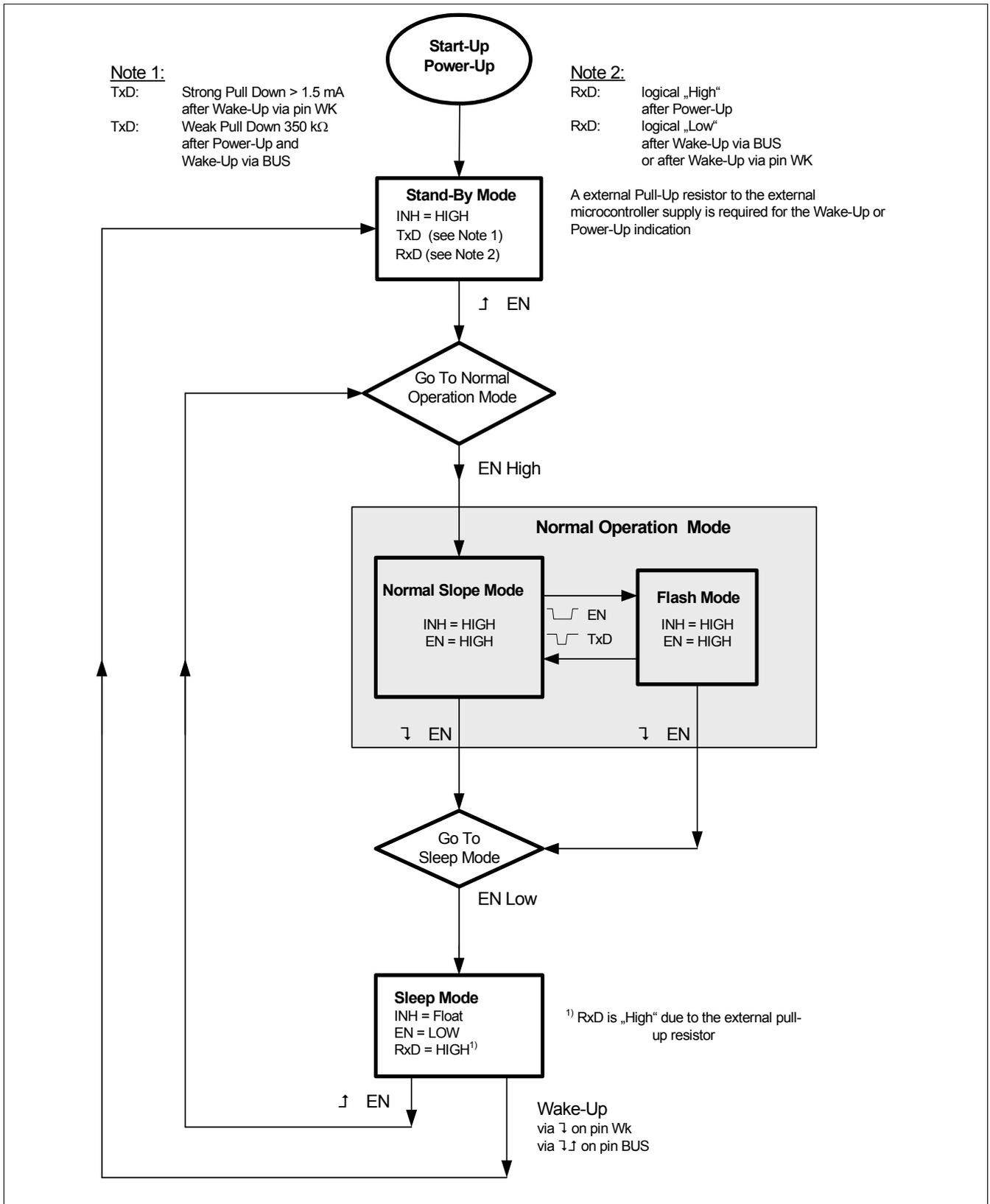


Figure 4 Operation Mode State Diagram

The IFX1021SJ has 3 major operation modes:

- Stand-By mode
- Normal Operation mode
- Sleep mode

The Normal Operation mode contains 2 sub-operation modes, which differentiate by the slew rate control of the LIN Bus signal (see [Figure 4](#)).

Sub-operation modes with different slew rates on the BUS pin:

- Normal Slope mode, for data transmission rates up to 20 kBaud
- Flash mode, for programming of the external microcontroller

The operation mode of the IFX1021SJ is selected by the EN pin. (see [Figure 4](#)).

Table 1 Operating modes

Mode	EN	INH	TxD	RxD	LIN Bus Termination	Comments
Sleep	Low	Floating	Low	High ¹⁾	High Impedance	No wake-up request detected
Stand-By	Low	High	Low High ²⁾	Low High ¹⁾	30 kΩ (typical)	RxD "Low" after local Wake-Up (pin WK) or bus Wake-Up (pin BUS) RxD "High" after Power-Up TxD strong pull down after local Wake-Up (WK pin) ²⁾ TxD weak pull down after bus Wake-Up (pin BUS) or Power-Up ²⁾
Normal Operation	High	High	Low High	Low High	30 kΩ (typical)	RxD reflects the signal on the BUS TxD driven by the microcontroller

1) A pull-up resistor to the external microcontroller supply is required.

2) The TxD input needs an external termination to indicate a "High" or a "Low" signal. The external termination could be a pull-up resistor or an active microcontroller output.

4.2 Normal Operation Mode

The IFX1021SJ enters the Normal Operation mode after the microcontroller sets EN to "High" (see [Figure 4](#)). In Normal Operation mode the LIN bus receiver and the LIN bus transmitter are active. Data from the microcontroller is transmitted to the LIN bus via the TxD pin, the receiver detects the data stream on the LIN bus and forwards it to the RxD output pin. In Normal Operation mode, the INH pin is "High" (set to V_S) and the bus termination is set to 30 kΩ.

Normal Slope mode and the Flash mode are Normal Operation modes and in these sub-modes the behavior of the INH pin and the bus termination is the same. Per default the IFX1021SJ always enters into Normal Slope mode, either from Sleep mode or from Stand-By mode. The Flash mode can only be entered from Normal Slope mode.

In order to avoid any bus disturbance during a mode change, the output stage of the IFX1021SJ is disabled and set to recessive state during the mode change procedure. To release the IFX1021SJ for data communication on the LIN bus, the TxD pin needs to be set to "High" for the time $t_{to,rec}$.

4.2.1 Normal Slope Mode

In Normal Slope mode data transmission rates up to 20 kBauds are possible. Setting the EN pin to “High” starts the transition to Normal Slope mode. (see [Figure 5](#)).

The mode change to Normal Slope mode is defined by the time t_{MODE} . The time t_{MODE} specifies the delay time between the threshold, where the EN pin detects a “High” input signal, and the actual mode change of IFX1021SJ into Normal Slope mode. Entering in Normal Operation mode, the IFX1021SJ always enters per default into Normal Slope mode. The signal on the TxD pin is not relevant for entering into Normal Slope mode.

Finally to release the data communication it is required to set the TxD pin to “High” for the time $t_{to,rec}$.

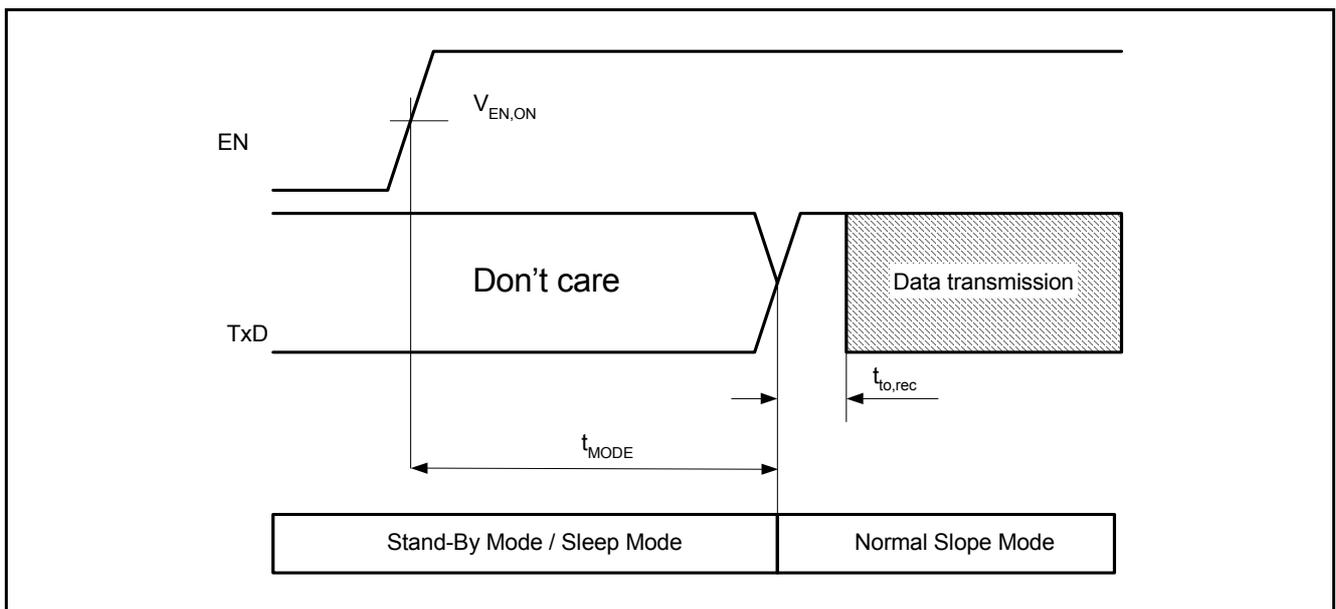


Figure 5 Timing to enter Normal Slope Mode

4.2.2 Flash Mode

In Flash mode it is possible to transmit and receive LIN messages on the LIN bus. The slew rate control mechanism of the LIN bus signal is disabled. This allows higher data transmission rates, disregarding the EMC limitations of the LIN network. The Flash mode is intended to be used during the ECU production for programming the microcontroller via the LIN bus interface.

The IFX1021SJ can be set to Flash mode only from Normal Slope mode (see [Figure 4](#)). Flash mode is entered by setting the EN pin to “Low” for the time t_{fl1} and generating a falling and a rising edge at the TxD pin with the timing t_{fl2} , t_{fl3} and t_{fl4} (see [Figure 6](#)). Leaving the Flash mode by the same sequence, sets the IFX1021SJ back to Normal Slope mode. Finally to release the data transmission it is required to set the TxD pin to “High” for the time $t_{to,rec}$.

Additionally the IFX1021SJ can leave the Flash mode as well by switching only the EN pin to “Low”. By applying this “Low” signal to the EN pin the IFX1021SJ is put into Sleep mode.

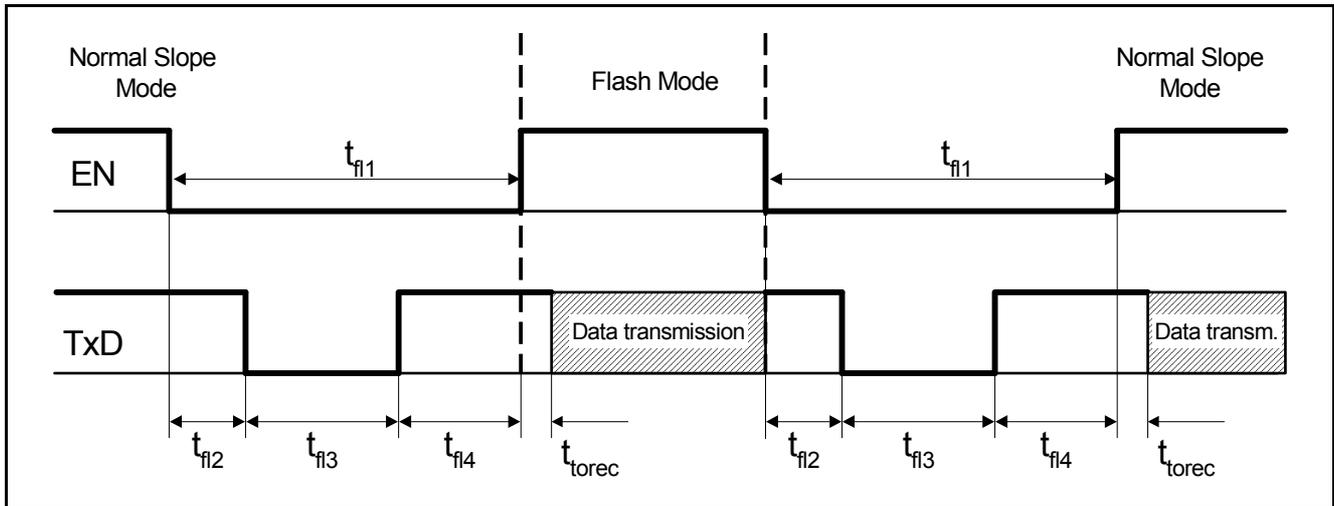


Figure 6 Timing to enter and leave Flash Mode

4.3 Stand-By Mode

The Stand-By mode is entered automatically after:

- A Power-Up event at the supply V_S .
- A bus Wake-Up event at the pin BUS.
- A local Wake-Up event at the pin WK.
- A power on reset caused by power supply V_S
- In Stand-By mode the Wake-Up sources are monitored by the TxD and RxD pins.

In Stand-By mode no communication on the LIN Bus is possible. The output stage is disabled and the LIN Bus termination remains activated. The RxD and the TxD pin are used to indicate the Wake-Up source or a Power-Up event. The RxD pin remains “Low” after a local Wake-Up event on the pin WK and a bus Wake-Up event on the LIN bus. A Power-Up event is indicated by a logical “High” on the RxD pin. The signal on the TxD pin indicates the Wake-Up source, a weak pull-down signals a bus Wake-Up event on the LIN bus and a strong pull-down signals a local Wake-Up event caused by the WK pin (see [Table 1](#) and [Table 2](#)). In order to detect a Wake-Up event via the TxD pin, the external microcontroller output needs to provide a logical “High” signal. The Wake-Up flags indicating the Wake-Up source on the pins TxD and RxD are reset by changing the operation mode to Normal Operation mode.

The signal on the EN pin remains “Low” due to an internal pull-down resistor. Setting the EN pin to “High”, by the microcontroller returns the IFX1021SJ to Normal Operation mode. In Stand-By mode the INH output is switching to V_S . The INH output can be used to control external devices like a voltage regulator.

Table 2 Logic table for wake up monitoring

power up	WK	BUS	RxD ¹⁾	TxD ²⁾	Remarks
Yes	1	1	1	1	No Wake-Up, Power-Up event
No	Wake-Up ³⁾	1	0	0	Wake via wake pin
No	1	Wake-Up ⁴⁾	0	1	Wake via BUS

1) To indicate the Wake-Up sources via the RxD pin, a pull-up resistor to the external microcontroller supply is required.
 2) The TxD input needs an external termination to indicate a “High” or a “Low” signal. The external termination could be a pull-up resistor or an active microcontroller output.
 3) A local Wake-Up event is considered after a low signal on the pin WK (see [Chapter 4.7](#)).
 4) A bus Wake-Up event is considered after a low to high transition on the LIN bus (see [Chapter 4.6](#))

4.4 Sleep Mode

In order to reduce the current consumption the IFX1021SJ offers a Sleep mode. In Sleep mode the quiescent current on V_S and the leakage current on the pin BUS are cut back to a minimum.

To switch the IFX1021SJ from Normal Operation mode to Sleep mode, the EN pin has to be set to “Low”. Conversely a logical “High” on the EN pin sets the device directly back to Normal Operation mode (see [Figure 4](#)).

While the IFX1021SJ is in Sleep mode the following functions are available:

- The output stage is disabled and the internal bus terminations are switched off (High Impedance on the pin BUS). The internal current source on the bus pin ensures that the level on the pin BUS remains recessive and protects the LIN network against accidental bus Wake-Up events.
- The receiver stage is turned off.
- RxD output pin is “High” if a pull-up resistor is connected to the external microcontroller supply. The TxD pin is disabled. The logical state on the TxD pin is “Low”, due to the internal pull-down resistor.
- The INH output is switched off and floating.
- The bus Wake-Up comparator is active and turns the IFX1021SJ to Stand-By mode in case of a bus Wake-Up event.
- The WK pin is active and turns the IFX1021SJ to Stand-By mode in case of a local Wake-Up.
- The EN pin remains active, switching the EN pin to “High” changes the operation mode to Normal Slope mode.

4.5 Wake-Up Events

A Wake-Up event changes the operation mode of the IFX1021SJ from Sleep mode to Stand-By mode. There are 3 different ways to wake-up the IFX1021SJ from Sleep mode.

- Bus Wake-Up via a minimum dominant signal ($t_{WK,bus}$) on the pin BUS.
- Local Wake-Up via a minimum dominant time (t_{WK}) on the WK pin.
- Mode change from Sleep mode to Normal Operation mode, by setting the EN pin to logical “High”.

4.6 Bus Wake-Up via LIN bus

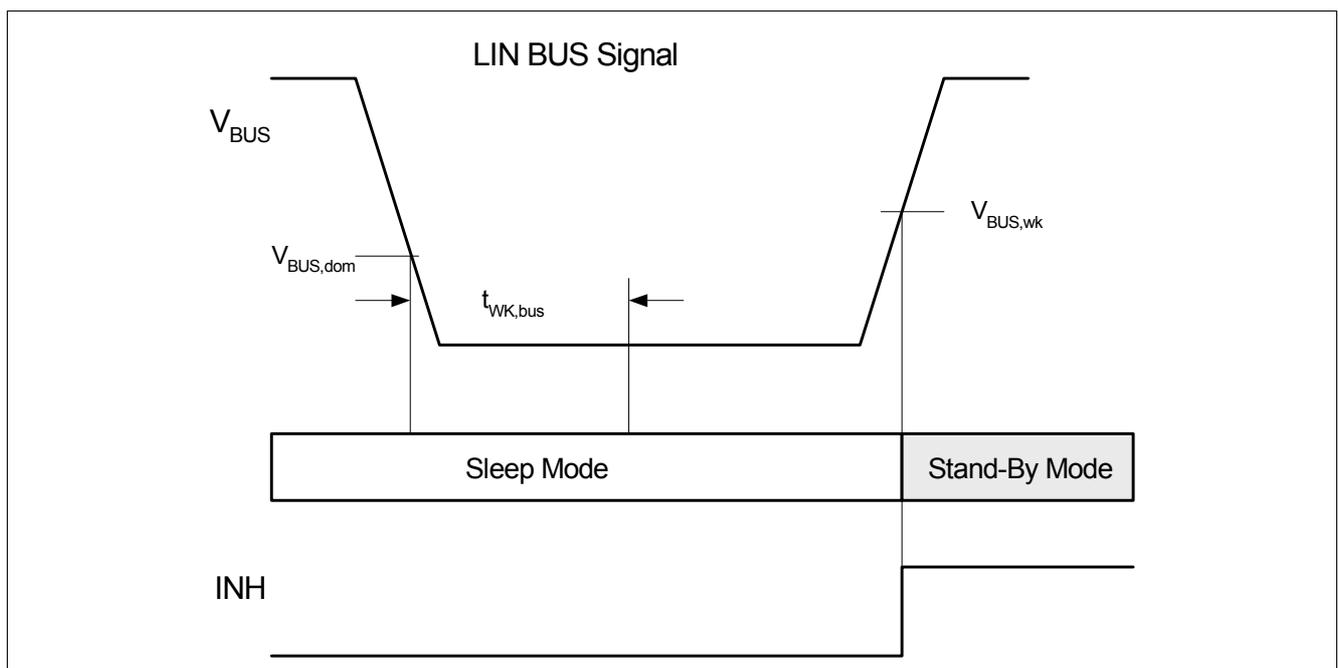


Figure 7 Bus Wake-Up behavior

The bus Wake-Up event, often called remote Wake-Up, changes the operation mode from Sleep mode to Stand-By mode. A falling edge on the LIN bus, followed by a dominant bus signal $t > t_{WK,bus}$ results in a bus Wake-Up event. The mode change to Stand-By mode becomes active with the following rising edge on the LIN bus. The IFX1021SJ remains in Sleep mode until it detects a change from dominant to recessive on the LIN bus (see [Figure 7](#)).

In Stand-By mode the TxD pin indicates the source of the Wake-Up event. A weak pull-down on the pin TxD indicates a bus Wake-Up event (see [Figure 4](#)). The RxD pin signals if a Wake-Up event occurred or the power-up event. A “Low” signal on the RxD pin reports a local or bus Wake-Up event, a logical “High” signal on RxD indicates a power-up event.

4.7 Local Wake-Up

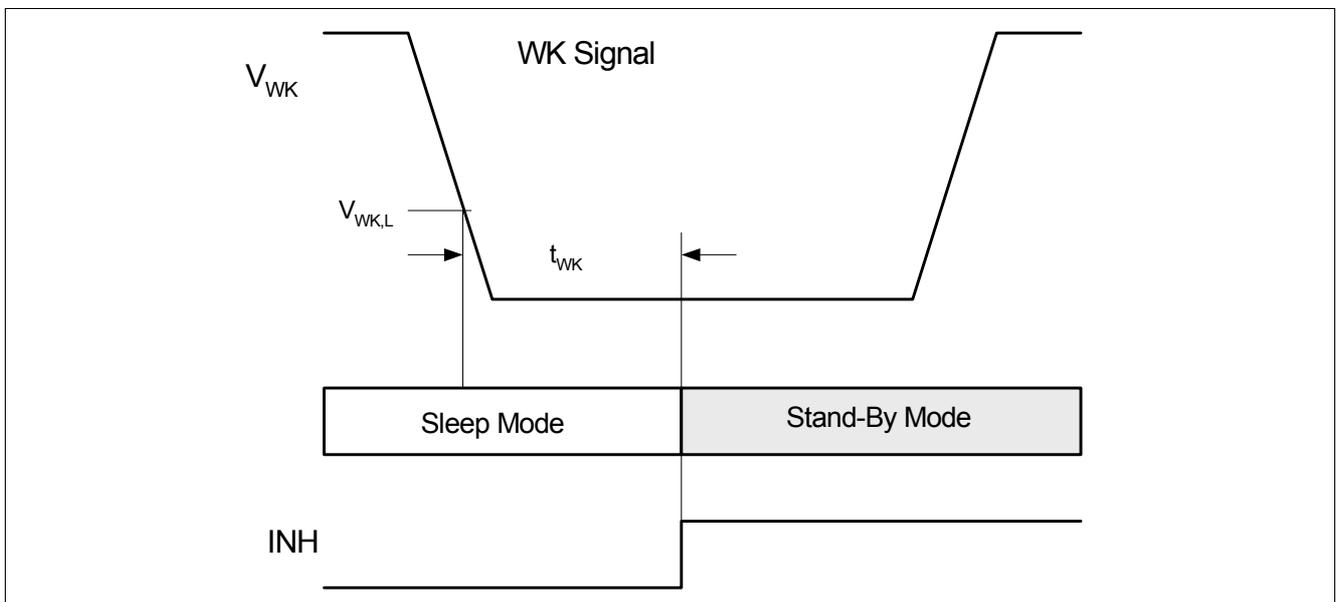


Figure 8 Local Wake-Up behavior

Beside the remote Wake-Up, a Wake-Up of the IFX1021SJ via the WK pin is possible. This type of wake-up event is called “Local Wake Up”. A falling edge on the WK pin followed by a “Low” signal for $t > t_{WK}$ results in a local Wake-Up (see [Figure 8](#)) and changes the operation mode to Stand-By mode.

In Stand-By mode the TxD pin indicates the source of the Wake-Up event. A strong pull-down on the pin TxD indicates a bus Wake-Up event (see [Figure 4](#)). The RxD pin signals if a Wake-Up event or the Power-Up event occurred. A “Low” signal on the RxD pin reports a local or bus Wake-Up event, a logical “High” signal on RxD indicates a Power-Up event.

4.8 Mode Transition via EN pin

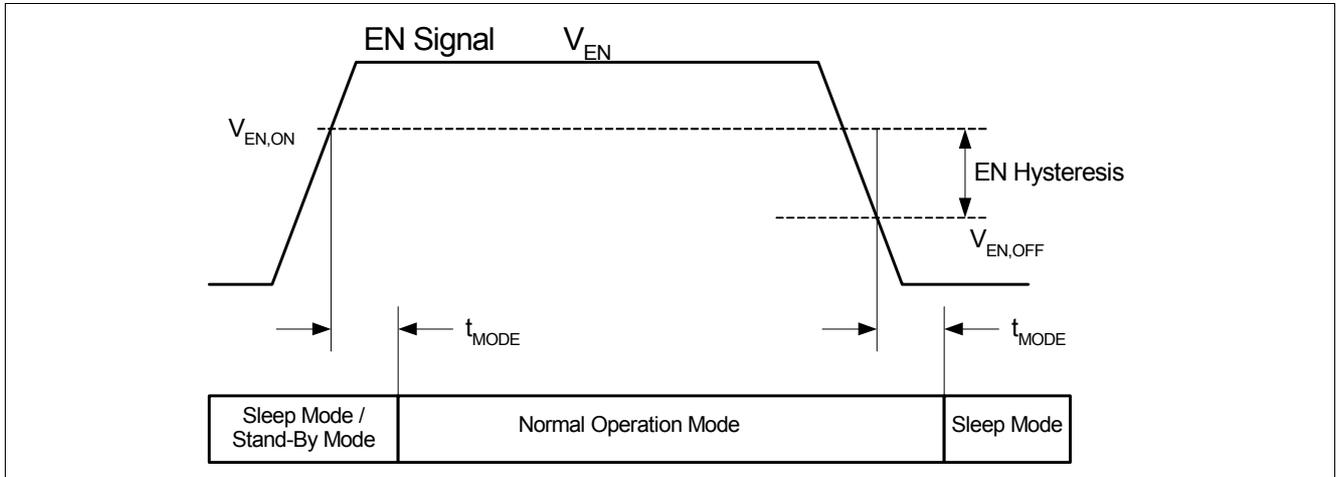


Figure 9 Mode Transition via EN pin

It is also possible to change from Sleep mode to Normal Operation mode by setting the EN pin to logical “High”. This feature is useful if the external microcontroller is continuously powered, the microcontroller power-supply is not controlled by the INH pin. The EN pin has an integrated pull-down resistor to ensure the device remains in Sleep or Stand-By mode even if the voltage on the EN pin is floating. The EN pin has an integrated hysteresis (see [Figure 9](#)).

A transition from logical “High” to logical “Low” on the EN pin changes the operation mode from Normal Operation mode to Sleep mode. If the IFX1021SJ is already in Sleep mode, changing the EN from “Low” to “High” results into a mode change from Sleep mode to Normal Operation mode. If the device is in Stand-By mode a change from “Low” to “High” on the EN pin changes the mode to Normal Operation mode, as well (see [Figure 4](#)).

4.9 TxD Time Out function

If the TxD signal is dominant for a time $t > t_{\text{timeout}}$ the TxD time-out function deactivates the transmission of the LIN signal to the bus and disables the output stage. This is realized to prevent the bus from being blocked by a permanent “Low” signal on the TxD pin, caused by an error on the external microcontroller (see [Figure 10](#)).

The transmission is released again, after a rising edge at the pin TxD has been detected.

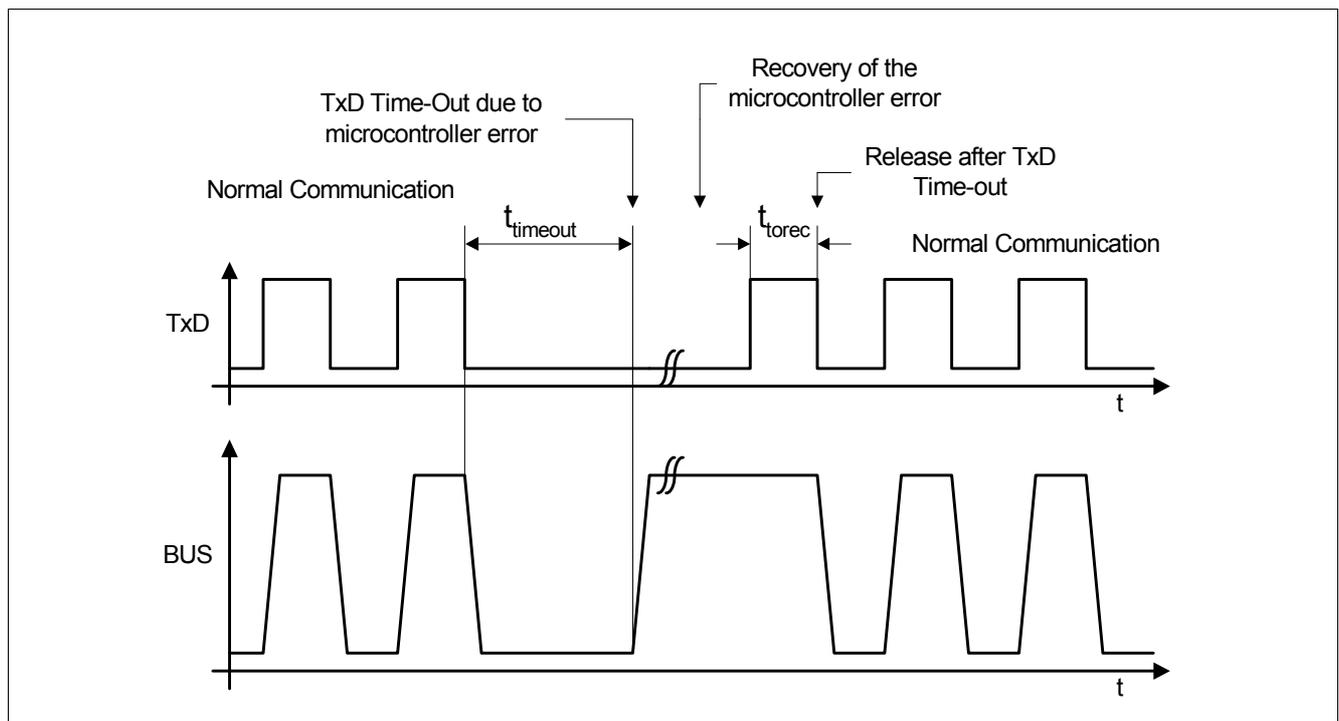


Figure 10 TxD Time-Out function

4.10 Over Temperature protection

The IFX1021SJ has an integrated over temperature sensor to protect the device against thermal overstress on the output stage. In case of an over temperature event, the temperature sensor will disable the output stage (see [Figure 1](#)). An over temperature event will not cause any mode change and won't be indicated by the RxD pin or the TxD pin. When the junction temperature falls below the thermal shut down level $T_J < T_{jSD}$, the output stage is re-enabled and data communication can start again on the LIN bus. A 10°C hysteresis avoids toggling during the temperature shut down.

4.11 3.3 V and 5 V Logic Capability

The IFX1021SJ can be used for 3.3 V and 5 V microcontrollers. The inputs and the outputs are capable to operate with both voltage levels. The RxD output must have an external pull-up resistor to the microcontroller supply to define the output voltage level.

4.12 BUS Short to GND Feature

In case the LIN bus is shorted to GND (i.e. causing a permanent dominant state on the bus) a continuous current would flow via the termination paths of the LIN devices. For the slaves this path is the internal 30 kΩ termination while for the master it is the internal 30 kΩ path as well as the 1 kΩ master termination. The IFX1021SJ allows to reduce the short-circuit current in such a failure state to a minimum:

Once the microcontroller has detected the bus short by monitoring a continuous dominant level on RxD, it simply needs to put the IFX1021SJ in Sleep Mode. In this Mode the internal 30 kΩ termination is switched off from V_S

and only a weak pull-up current source remains active. In addition the IFX1021SJ offers with its “Bus Short to GND feature” the possibility to also switch off the master termination from V_S . To use this feature the master termination of the LIN bus must be connected to the INH pin of the IFX1021SJ instead of connecting it directly to V_S (see [Figure 14](#) and [Figure 15](#)). The INH pin of the IFX1021SJ can drive V_S as an output that is switched off during Sleep Mode. In this configuration the master termination also will be switched off in Sleep Mode and the failure current can be reduced to a minimum. This feature is of special interest for battery operated systems where battery discharge during sleep mode might be critical.

4.13 LIN Specifications 1.2, 1.3, 2.0 and 2.1

The device fulfills the Physical Layer Specification of LIN 1.2, 1.3, 2.0 and 2.1.

The differences between LIN specification 1.2 and 1.3 is mainly the physical layer specification. The reason was to improve the compatibility between the nodes.

The LIN specification 2.0 is a super set of the 1.3 version. The 2.0 version offers new features. However, it is possible to use the LIN 1.3 slave node in a 2.0 node cluster, as long as the new features are not used. Vice versa it is possible to use a LIN 2.0 node in the 1.3 cluster without using the new features.

In terms of the physical layer the LIN 2.1 Specification doesn't include any changes and is fully compliant to the LIN Specification 2.0.

LIN 2.1 is the latest version of the LIN specification, released in December 2006.

5 General Product Characteristics

5.1 Absolute Maximum Ratings

Table 3 Absolute Maximum Ratings Voltages, Currents and Temperatures¹⁾

All voltages with respect to ground; positive current flowing into pin;
(unless otherwise specified)

Pos.	Parameter	Symbol	Limit Values		Unit	Remarks
			Min.	Max.		
Voltages						
5.1.1	Supply voltage	V_S	-0.3	40	V	LIN Spec 2.1 Param. 10
5.1.2	Bus and WK input voltage versus GND versus V_S	$V_{BUS,G}$	-40	40	V	–
		V_{BUS,V_S}	-40	40	V	
5.1.3	Logic voltages at EN, TxD, RxD	V_{logic}	-0.3	5.5	V	–
5.1.4	INH Voltage versus GND versus V_S	$V_{INH,G}$	-0.3	40	V	–
		V_{INH,V_S}	-40	0.3	V	
Currents						
5.1.5	Output current at INH	I_{INH}	-150	80	mA	²⁾
Temperatures						
5.1.6	Junction temperature	T_j	-40	150	°C	–
5.1.7	Storage temperature	T_s	-55	150	°C	–
ESD Resistivity						
5.1.8	Electrostatic discharge voltage at V_S , Bus, WK versus GND	V_{ESD}	-6	6	kV	Human Body Model (100pF via 1.5 k Ω) ³⁾
5.1.9	Electrostatic discharge voltage all pins	V_{ESD}	-2	2	kV	Human Body Model (100pF via 1.5 k Ω) ³⁾

1) Not subject to production test, specified by design

2) Output current is internally limited to -150 mA

3) ESD susceptibility HBM according to EIA / JESD 22-A 114

Note: Stresses above the ones listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" normal operating range. Protection functions are not designed for continuous repetitive operation.

5.2 Functional Range

Table 4 Operating Range

Pos.	Parameter	Symbol	Limit Values			Unit	Remarks
			Min.	Typ.	Max.		
Supply voltages							
5.2.1	Extended Supply Voltage Range for Operation	$V_{S(ext)}$	5	–	40	V	Parameter deviations possible
5.2.2	Supply Voltage range for Normal Operation	$V_{S(nor)}$	7	–	27	V	LIN Spec 2.1 Param. 10
Thermal parameters							
5.2.3	Junction temperature	T_j	-40	–	125	°C	1)

1) Not subject to production test, specified by design

Note: Within the functional range the IC operates as described in the circuit description. The electrical characteristics are specified within the conditions given in the related electrical characteristics table.

5.3 Thermal Characteristics

Table 5 Thermal Resistance¹⁾

Pos.	Parameter	Symbol	Limit Values			Unit	Remarks
			Min.	Typ.	Max.		
Thermal Resistance							
5.3.1	Junction to Soldering Point	R_{thJSP}	–	–	25	K/W	measured on pin 5
5.3.2	Junction ambient	R_{thJA}	–	130	–	K/W	2)
Thermal Shutdown Junction Temperature							
5.3.3	Thermal shutdown temp.	T_{jSD}	150	175	190	°C	–
5.3.4	Thermal shutdown hyst.	ΔT	–	10	–	K	–

1) Not subject to production test, specified by design

2) JESD 51-2, 51-3, FR4 76,2 mm x 114,3 mm x 1,5 mm, 70 μ m Cu, minimal footprint, $T_a = 27^\circ\text{C}$

6 Electrical Characteristics

6.1 Functional Device Characteristics

Table 6 Electrical Characteristics

7.0 V < V_S < 27 V; $R_{BUS} = 500 \Omega$; $-40 \text{ }^\circ\text{C} < T_j < 125 \text{ }^\circ\text{C}$; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Pos.	Parameter	Symbol	Limit Values			Unit	Remarks
			Min.	Typ.	Max.		
Current Consumption							
6.1.1	Current consumption at V_S	$I_{S,rec}$	0.5	1.1	3.0	mA	Recessive state, without R_L ; $V_S = 13.5 \text{ V}$; $V_{TxD} = \text{“High”}$
6.1.2	Current consumption at V_S Dominate State	$I_{S,dom}$	–	1.5	5.0	mA	Dominant state, without R_L ; $V_S = 13.5 \text{ V}$; $V_{TxD} = 0 \text{ V}$
6.1.3	Current consumption at V_S in sleep mode	$I_{S,sleep}$	–	5	12	μA	Sleep mode. $V_S = 18 \text{ V}$; $V_{WK} = V_S = V_{BUS}$;
6.1.4	Current consumption at V_S in sleep mode	$I_{S,sleep,typ}$	–	–	10	μA	Sleep mode, $T_j < 85 \text{ }^\circ\text{C}$ $V_S = 13.5 \text{ V}$; $V_{WK} = V_S = V_{BUS}$
6.1.5	Current consumption in sleep mode bus shorted to GND	I_{S,ilk,SC_GND}	–	45	100	μA	Sleep mode, $V_S = 13.5 \text{ V}; V_{BUS} = 0\text{V}$
Receiver Output: RxD							
6.1.6	HIGH level leakage current	$I_{RD,H,leak}$	-5	–	5	μA	$V_{RxD} = 5\text{V}; V_{BUS} = V_S$
6.1.7	LOW level output current	$I_{RD,L}$	1.7	–	10	mA	$V_{RxD} = 0.9\text{V}, V_{BUS} = 0\text{V}$
Transmission Input: TxD							
6.1.8	HIGH level input voltage range	$V_{TD,H}$	2	–	5.5	V	Recessive state
6.1.9	Input hysteresis	$V_{TD,hys}$	150	300	450	mV	¹⁾
6.1.10	LOW level input voltage range	$V_{TD,L}$	-0.3	–	0.8	V	Dominant state
6.1.11	Pull-down resistance	R_{TD}	100	350	800	k Ω	$V_{TxD} = \text{High}$
6.1.12	Dominant current standby mode after Wake-Up	$I_{TD,L}$	1.5	3	10	mA	$V_{TxD} = 0.9 \text{ V}; V_{WK} = 0 \text{ V};$ $V_S = 13.5 \text{ V}$
6.1.13	Input capacitance	C_i	–	5	–	pF	¹⁾

Electrical Characteristics
Table 6 Electrical Characteristics (cont'd)

7.0 V < V_S < 27 V; $R_{BUS} = 500 \Omega$; $-40 \text{ }^\circ\text{C} < T_J < 125 \text{ }^\circ\text{C}$; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Pos.	Parameter	Symbol	Limit Values			Unit	Remarks
			Min.	Typ.	Max.		
Enable Input: EN							
6.1.14	HIGH level input voltage range	$V_{EN,ON}$	2	–	5.5	V	Normal Operation mode
6.1.15	LOW level input voltage range	$V_{EN,OFF}$	-0.3	–	0.8	V	Sleep mode or Stand-By mode
6.1.16	Input hysteresis	$V_{EN,hys}$	150	300	450	mV	¹⁾
6.1.17	Pull-down resistance	R_{EN}	15	30	60	k Ω	–
6.1.18	Input capacitance	$C_{i_{EN}}$	–	5	–	pF	¹⁾
Inhibit, Master Termination Output: INH							
6.1.19	Inhibit R_{on} resistance	$R_{INH,on}$	22	36	50	Ω	$I_{INH} = -15 \text{ mA}$
6.1.20	Maximum INH output current	I_{INH}	-150	-110	-40	mA	$V_{INH} = 0 \text{ V}$
6.1.21	Leakage current	$I_{INH,Ik}$	-5.0	–	5.0	μA	Sleep mode; $V_{INH} = 0 \text{ V}$
Wake Input: WK							
6.1.22	High level input voltage	$V_{WK,H}$	$V_S - 1 \text{ V}$	–	$V_S + 3 \text{ V}$	V	tested $V_S = 13.5 \text{ V}$;
6.1.23	Low level input voltage	$V_{WK,L}$	-0.3	–	$V_S - 4 \text{ V}$	V	tested $V_S = 13.5 \text{ V}$;
6.1.24	Pull-up current	$I_{WK,PU}$	-60	-20	-3	μA	–
6.1.25	High level leakage current	$I_{WK,H,leak}$	-5	–	5	μA	$V_S = 0 \text{ V}$; $V_{WK} = 40 \text{ V}$
6.1.26	Dominant time for Wake-Up	t_{WK}	30	–	150	μs	–
6.1.27	Input Capacitance	$C_{i_{WK}}$	–	15	–	pF	¹⁾
Bus Receiver: BUS							
6.1.28	Receiver threshold voltage, recessive to dominant edge	V_{th_dom}	$0.4 \times V_S$	$0.45 \times V_S$	–	V	–
6.1.29	Receiver dominant state	V_{BUSdom}	$V_S - 40 \text{ V}$	–	$0.4 \times V_S$	V	LIN Spec 2.1 (Par. 17) ²⁾
6.1.30	Receiver threshold voltage, dominant to recessive edge	V_{th_rec}	–	$0.55 \times V_S$	$0.6 \times V_S$	V	–
6.1.31	Receiver recessive state	V_{BUSrec}	$0.6 \times V_S$	–	$1.15 \times V_S$	V	LIN Spec 2.1 (Par. 18) ³⁾
6.1.32	Receiver center voltage	V_{BUS_CNT}	$0.475 \times V_S$	$0.5 \times V_S$	$0.525 \times V_S$	V	LIN Spec 2.1 (Par. 19) ⁴⁾
6.1.33	Receiver hysteresis	V_{HYS}	$0.07 \times V_S$	$0.12 \times V_S$	$0.175 \times V_S$	V	LIN Spec 2.1 (Par. 20) ⁵⁾
6.1.34	Wake-Up threshold voltage	$V_{BUS,wk}$	$0.40 \times V_S$	$0.5 \times V_S$	$0.6 \times V_S$	V	–
6.1.35	Dominant time for bus Wake-Up	$t_{WK,bus}$	30	–	150	μs	–

Electrical Characteristics
Table 6 Electrical Characteristics (cont'd)

7.0 V < V_S < 27 V; R_{BUS} = 500 Ω; -40 °C < T_J < 125 °C; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Pos.	Parameter	Symbol	Limit Values			Unit	Remarks
			Min.	Typ.	Max.		
Bus Transmitter BUS							
6.1.36	Bus recessive output voltage	V _{BUS,ro}	0.8 × V _S	–	V _S	V	V _{TxD} = high Level
6.1.37	Bus dominant output voltage maximum load	V _{BUS,do}	–	–	1.2	V	V _{TxD} = 0 V; R _L = 500 Ω 6.0 ≤ V _S ≤ 7.3 V; 7.3 < V _S ≤ 10 V; 10 < V _S ≤ 18 V; (see Figure 12)
			–	–	0.2 × V _S	V	
			–	–	2.0	V	
6.1.38	Bus short circuit current	I _{BUS_LIM}	70	100	150	mA	V _{BUS} = 13.5 V; LIN Spec 2.1 (Par. 12);
6.1.39	Leakage current	I _{BUS_NO_GND}	-1	-0.5	–	mA	V _S = 0 V; V _{BUS} = -12 V; LIN Spec 2.1 (Par. 15)
6.1.40	Leakage current	I _{BUS_NO_BAT}	–	1	8	μA	V _S = 0 V; V _{BUS} = 18 V; LIN Spec 2.1 (Par. 16)
6.1.41	Leakage current	I _{BUS_PAS_dom}	-1	-0.5	–	mA	V _S = 18 V; V _{BUS} = 0 V; LIN Spec 2.1 (Par. 13)
6.1.42	Leakage current	I _{BUS_PAS_rec}	–	1	8	μA	V _S = 8 V; V _{BUS} = 18 V; LIN Spec 2.1 (Par. 14)
6.1.43	Bus pull-up resistance	R _{slave}	20	30	47	kΩ	Normal mode LIN Spec 2.1 (Par. 26)
6.1.44	LIN output current	I _{BUS}	-60	-30	-5	μA	Sleep mode V _S = 13.5V V _{EN} = 0V
6.1.45	Input Capacitance	Ci _{BUS}		15	–	pF	¹⁾
Dynamic Transceiver Characteristics: BUS							
6.1.46	Propagation delay LIN bus to RxD Dominant to RxD Low Recessive to RxD High	t _{rx_pdf} t _{rx_pdr}	–	1	6	μs	LIN Spec 2.1 (Par. 31) R _{RxD} = 2.4 kΩ; C _{RxD} = 20 pF
			–	1	6	μs	
6.1.47	Receiver delay symmetry	t _{rx_sym}	-2	–	2	μs	LIN Spec 2.1 (Par. 32) t _{rx_sym} = t _{rx_pdf} - t _{rx_pdr} ; R _{RxD} = 2.4 kΩ; C _{RxD} = 20 pF
6.1.48	Delay time for mode change	t _{MODE}	–	–	150	μs	¹⁾ See Figure 5
6.1.49	TxD dominant time out	t _{timeout}	8	13	20	ms	V _{TxD} = 0 V
6.1.50	TxD dominant time out recovery time	t _{torec}	–	–	15	μs	¹⁾
6.1.51	EN toggling to enter the flash mode	t _{fl1}	25	35	50	μs	¹⁾ See Figure 6
6.1.52	TxD time for flash activation	t _{fl2}	5	–	–	μs	¹⁾ See Figure 6
		t _{fl3}	10	–	–		
		t _{fl4}	10	–	–		

Electrical Characteristics

Table 6 Electrical Characteristics (cont'd)

7.0 V < V_S < 27 V; R_{BUS} = 500 Ω; -40 °C < T_J < 125 °C; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Pos.	Parameter	Symbol	Limit Values			Unit	Remarks
			Min.	Typ.	Max.		
6.1.53	Duty cycle D1 (for worst case at 20 kBit/s)	D1	0.396	–	–		duty cycle 1 ⁶⁾ TH _{Rec} (max) = 0.744 × V _S ; TH _{Dom} (max) = 0.581 × V _S ; V _S = 7.0 ... 18 V; t _{bit} = 50 μs; D1 = t _{bus_rec(min)}/2 t_{bit}; LIN Spec 2.1 (Par. 27)}
6.1.54	Duty cycle D2 (for worst case at 20 kBit/s)	D2	–	–	0.581		duty cycle 2 ⁶⁾ TH _{Rec} (min) = 0.422 × V _S ; TH _{Dom} (min) = 0.284 × V _S ; V _S = 7.6 ... 18 V; t _{bit} = 50 μs; D2 = t _{bus_rec(max)}/2 t_{bit}; LIN Spec 2.1 (Par. 28)}

1) Not subject to production test, specified by design

2) Minimum limit specified by design

3) Maximum limit specified by design

4) $V_{BUS_CNT} = (V_{th_dom} - V_{th_rec})/2$;

5) $V_{HYS} = V_{BUSrec} - V_{BUSdom}$

6) Bus load concerning LIN Spec 2.1:

Load 1 = 1 nF / 1 kΩ = C_{BUS} / R_{BUS}

Load 2 = 6.8 nF / 660 Ω = C_{BUS} / R_{BUS}

Load 3 = 10 nF / 500 Ω = C_{BUS} / R_{BUS}

6.2 Diagrams

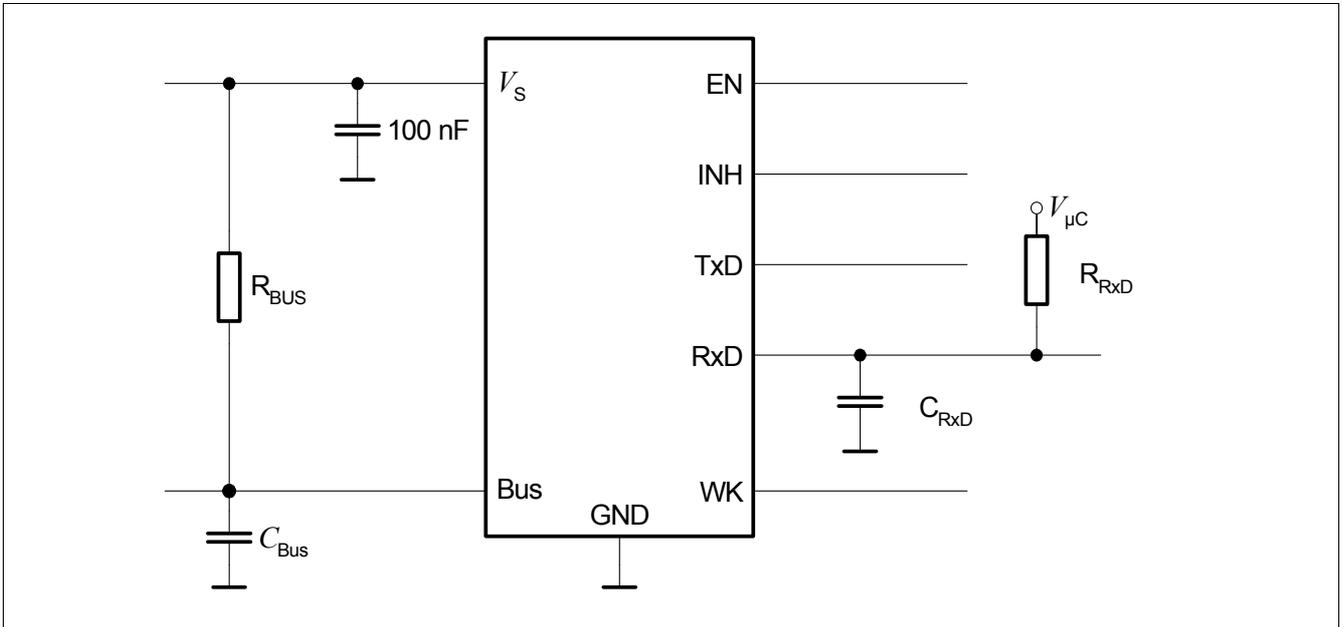


Figure 11 Simplified test circuit for dynamic characteristics

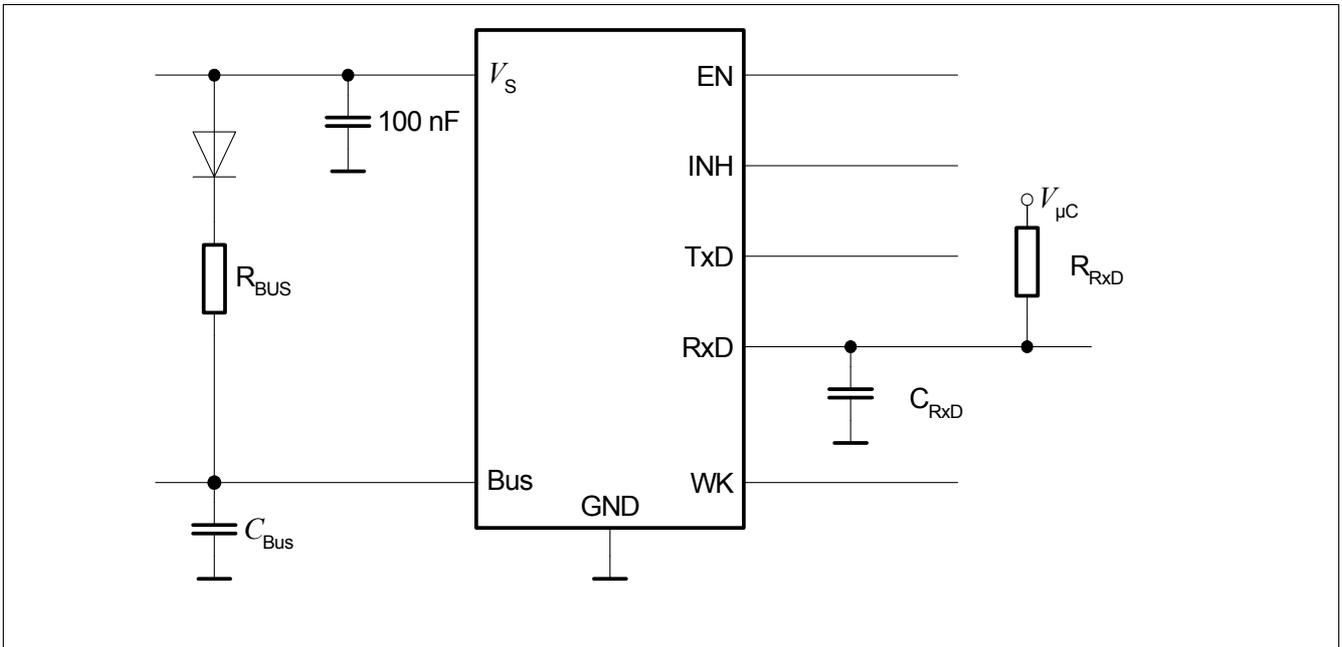


Figure 12 Simplified test circuit for static characteristics

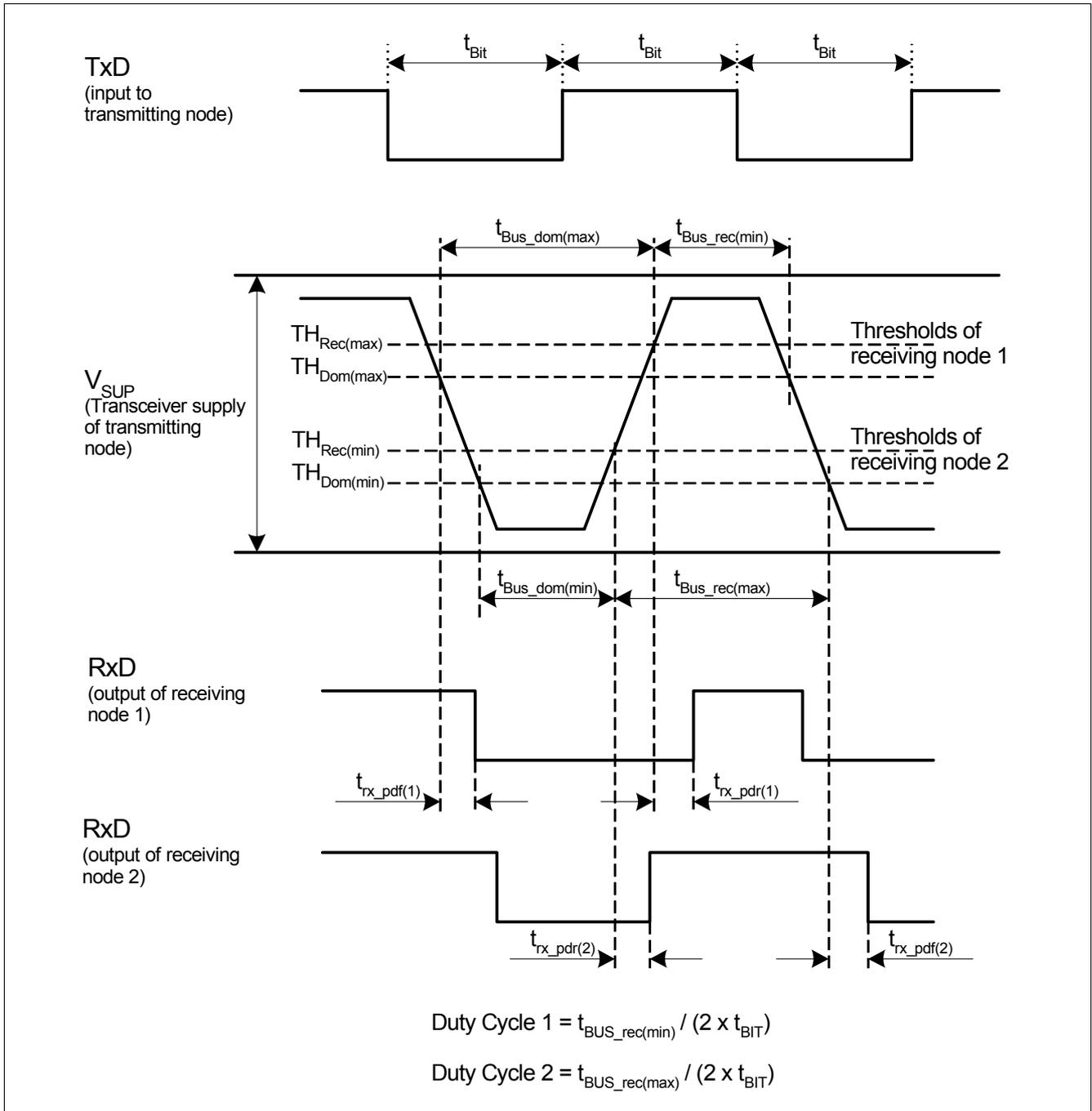


Figure 13 Timing diagram for dynamic characteristics

7 Application Information

7.1 Master Termination

To achieve the required timings for the dominant to recessive transition of the bus signal an additional external termination resistor of 1 k Ω is mandatory. It is recommended to place this resistor at the master node. To avoid reverse currents from the bus line into the supply line it is recommended to place a diode in series with the external pull-up. For small systems (low bus capacitance) the EMC performance of the system is supported by an additional capacitor of at least 1 nF at the master node (see [Figure 14](#) and [Figure 15](#)). The values for the Master Termination resistor and the bus capacitances influence the performance of the LIN network. They depend on the number of nodes inside the LIN network and on the parasitic cable capacitance of the LIN bus wiring.

7.2 External Capacitors

A capacitor of 10 μ F at the supply voltage input V_S buffers the input voltage. In combination with the required reverse polarity diode this prevents the device from detecting a power down conditions in case of negative transients on the supply line (see [Figure 14](#) and [Figure 15](#)).

The 100 nF capacitor close to the V_S pin of the IFX1021SJ is required to get the best EMC performance.

7.3 Application Example

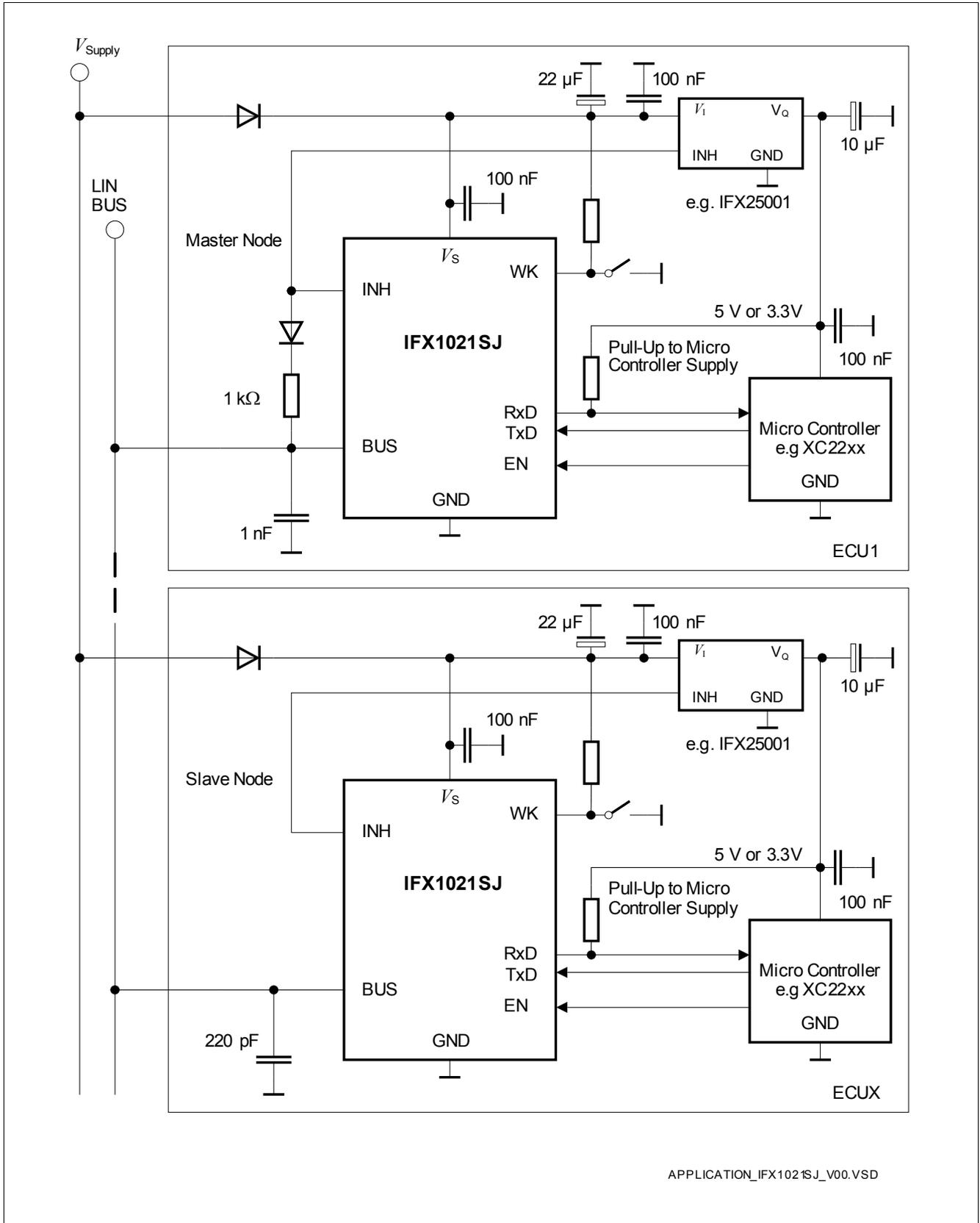


Figure 14 Simplified Application Circuit with Bus Short to GND Feature applied

8 Package Outlines

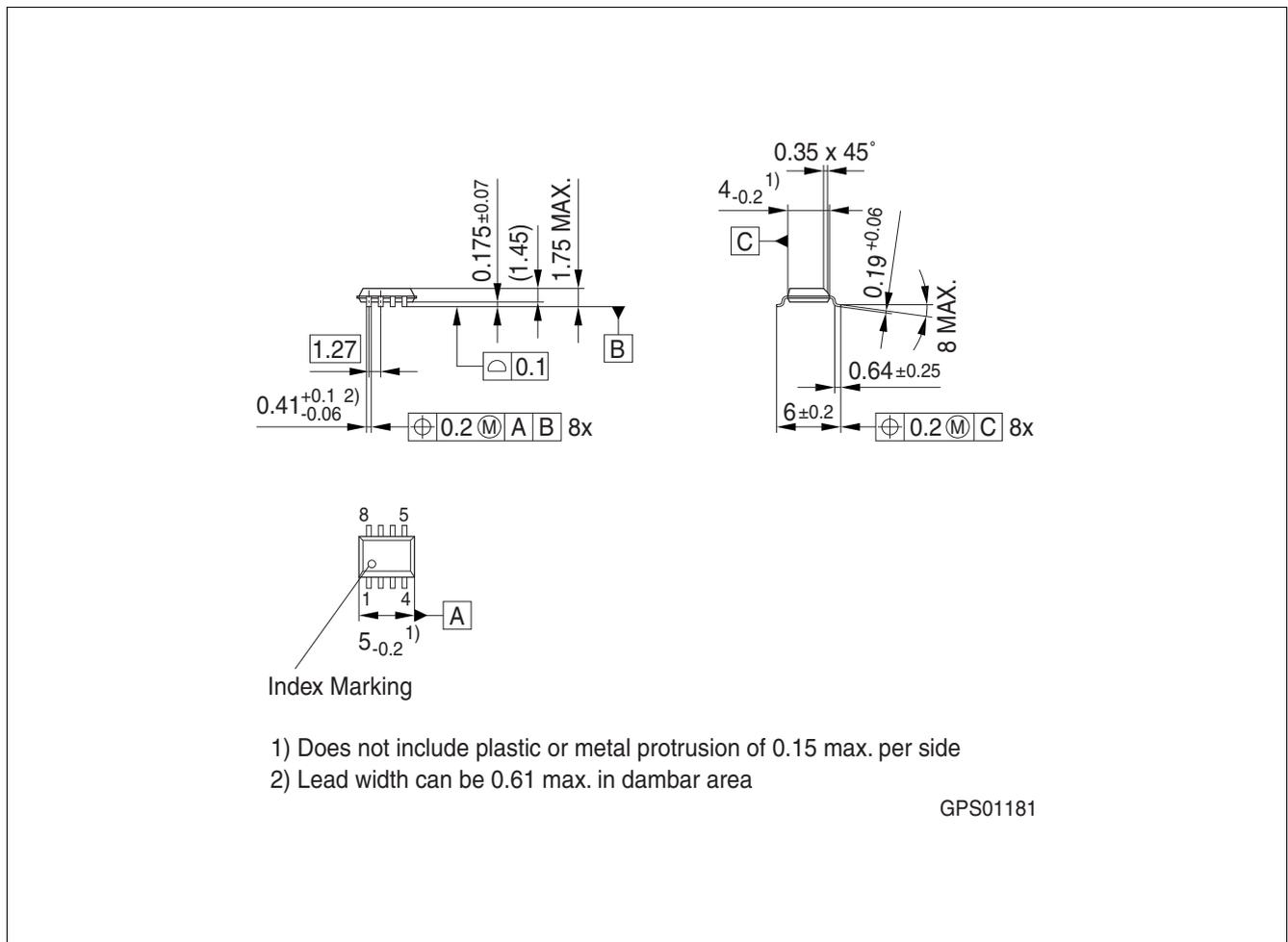


Figure 16 PG-DSO-8 (Plastic Dual Small Outline PG-DSO-8)

Green Product (RoHS compliant)

To meet the world-wide customer requirements for environmentally friendly products and to be compliant with government regulations the device is available as a green product. Green products are RoHS-Compliant (i.e. Pb-free finish on leads and suitable for Pb-free soldering according to IPC/JEDEC J-STD-020).

9 Revision History

Revision	Date	Changes
1.0	2011-09-20	Data Sheet - Initial Release

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